

# FDS2070N7

# 150V N-Channel PowerTrench® MOSFET

### **General Description**

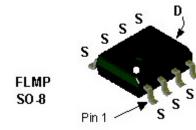
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low  $R_{\text{DS(ON)}}$  in a small package.

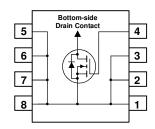
### **Applications**

- · Synchronous rectifier
- DC/DC converter

### **Features**

- 4.1 A, 150 V.  $R_{DS(ON)} = 78 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$   $R_{DS(ON)} = 88 \text{ m}\Omega$  @  $V_{GS} = 6.0 \text{ V}$
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS(ON)}}$
- High power and current handling capability
- Fast switching, low gate charge (38nC typical)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		150	V
V <sub>GSS</sub>	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	4.1	А
	- Pulsed		30	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	3.0	W
		(Note 1b)	1.8	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDS2070N7 FDS2070N7		13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	urce Avalanche Ratings					l
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 150 \text{ V}$ , $I_D = 10 \text{ A}$ L = 8.8 mH			440	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				10	Α
Off Char	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A}$	150			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		154		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 120 \text{ V},  V_{GS} = 0 \text{ V}$			1	μΑ
$I_{GSS}$	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, \ V_{DS} = 0 \text{ V}$			±100	nA
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	2	2.6	4	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		<b>-</b> 7		mV/°C
$R_{\text{DS(on)}}$	Static Drain–Source On–Resistance	$\begin{array}{c} V_{GS} = 10 \ V, & I_D = 4.1 \ A \\ V_{GS} = 6.0 V, & I_D = 3.8 \ A \\ V_{GS} = 10 \ V, & I_D = 4.1 \ A, T_J = 125 ^{\circ} C \end{array}$		57 60 111	78 88 160	mΩ
<b>g</b> FS	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_{D} = 4.1 \text{ A}$		24		S
Dynamic	Characteristics				•	•
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 75 \text{ V},  V_{GS} = 0 \text{ V},$		1884		pF
Coss	Output Capacitance	f = 1.0 MHz		102		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			35		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.6		Ω
Switchin	g Characteristics (Note 2)				•	•
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 75 \text{ V},  I_D = 1 \text{ A},$		10	20	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{GS} = 10 \text{ V},  R_{GEN} = 6 \Omega$		6	12	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			40	64	ns
t <sub>f</sub>	Turn-Off Fall Time			20	36	ns
Qg	Total Gate Charge	$V_{DS} = 75 \text{ V}, I_D = 4.1 \text{ A},$		38	53	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 10 V		8		nC
$Q_{gd}$	Gate-Drain Charge			11		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings	•		•	•
I <sub>s</sub>	Maximum Continuous Drain–Source				2.5	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_{S} = 2.5 \text{ A}  \text{(Note 2)}$		0.75	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 4.1A		75		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$ (Note 2)		404		nC

Notes:
1. R<sub>6JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width <  $300\mu s$ , Duty Cycle < 2.0%

# **Dimensional Outline and Pad Layout** -(0.65) (3.68)DRAIN TERMINAL **-**0.75 MIN (0.67)(2.36)DRAIN 2.80 MIN TERMINAL 7.40 0.70 BOTTOM VIEW 1.50 MIN 4.90±0.10-1.27 -1.40 3.81 3.81 <u>F</u>8 -4.10 MIN-LAND PATTERN RECOMMENDATION 3.90±0.10 SEE DETAIL A 0.51 0.35 (0.34) -⊕ 0.127M B A 1.27 -6.00±0.20-NOTES: UNLESS OTHERWISE SPECIFIED 0.1C ALL DIMENSIONS ARE IN MILLIMETERS. STANDARD LEAD FINISH: 20-80 MICROINCHES NICKEL/ 6 MICROINCHES MAX. PALLADIUM AND GOLD FLASH. NO JEDEC REGISTERED REFERENCE AS OF MARCH 2, 2000. 0.50 X 45° GAGE PLANE 0.36 1.60 MAX 0.90 0.50 SEATING PLANE (1.04) DETAIL A SCALE: 24:1

## **Typical Characteristics**

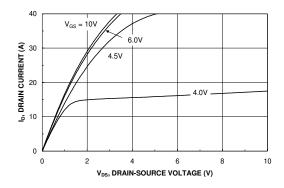


Figure 1. On-Region Characteristics.

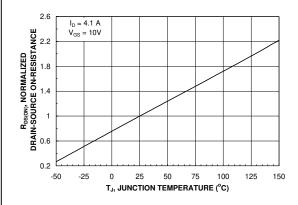


Figure 3. On-Resistance Variation with Temperature.

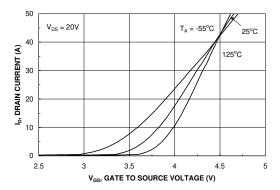


Figure 5. Transfer Characteristics.

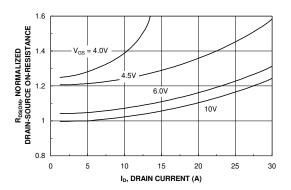


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

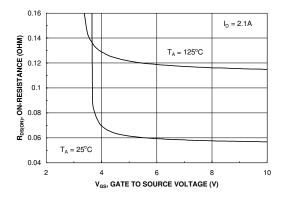


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

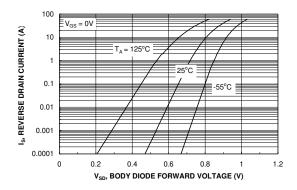
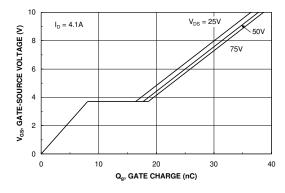


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Characteristics**



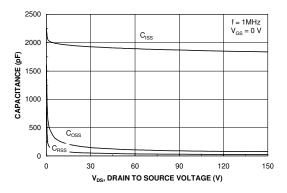


Figure 7. Gate Charge Characteristics.

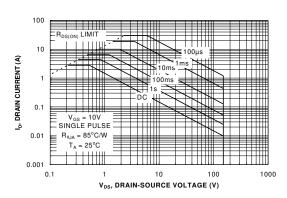


Figure 8. Capacitance Characteristics.

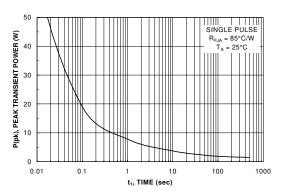


Figure 9. Maximum Safe Operating Area.



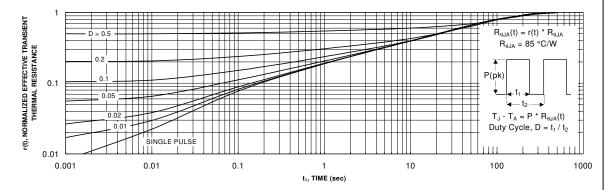


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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DOME™	GlobalOptoisolator™	MICROWIRE™	QS™	SyncFET™
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